

**Search Notes**

Application/Control No.

09/997,159

Examiner

Javier G. Blanco

Applicant(s)/Patent under  
Reexamination

SARVER, EDWIN JAY

Art Unit

3738

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
351	200	5/11/2007	JB
EAST Interference Search (see printout)		5/11/2007	JB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Results from the STIC search are included	8/13/2003	JB
EAST: general (i.e., no classification used) text/word search (see printout)	5/10/2007	JB
Backward/Forward search of best references	5/10/2007	JB
(optical ADJ2 model\$6) SAME (map OR mapping)	5/10/2007	JB
optical ADJ2 ((ray ADJ2 (trace OR tracing)) OR raytracing)	5/10/2007	JB
((wave\$1front) OR (wave ADJ front)) SAME ((ray ADJ2 (trace OR tracing)) OR raytracing)	5/10/2007	JB